

**Search Notes**

Application/Control No.

10/530,599

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

GUYER ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	203.1, 203.2, 203.3, 203.6	9/5/06 10/19/06 10/23/06 10/24/06	PL
250	339.14		PL
250	339.15		PL
250	342		PL
356	139.04	10/25/2006	PL
473	140-166	10/25/2006	PL
473	176, 192	10/25/2006	PL
473	199	10/25/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached) -USPAT, US- PGPUB, EPO, JPO, DERWENT	9/5/2006	PL
East (see attached) -USPAT, US- PGPUB, EPO, JPO, DERWENT	10/19/2006	PL
East (see attached) -USPAT, US- PGPUB, EPO, JPO, DERWENT	10/23/2006	PL
East (see attached) -USPAT, US- PGPUB, EPO, JPO, DERWENT	10/25/2006	PL